

**Notice of References Cited**

Application/Control No.

10/754,921

Applicant(s)/Patent Under  
Reexamination  
WELCH ET AL.

Examiner

DAVID TUROCY

Art Unit

1792

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*	B	US-5,879,808	03-1999	Wary et al.	428/411.1
*	C	US-5,075,174	12-1991	Pyle, Jeffrey	428/447
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*	N	JP 04173848 A	06-1992	Japan	SHIBAHARA et al.	
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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